Avalanche Diodes Array – 5D (ADA_5D)

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Proposta di nuova iniziativa CSN5 (2022-2025)

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CHARGE IDENTIFICATION of cosmic-ray (CR) ions with charge $1 \le Z \le 30$ with dE/dx $\propto Z^2$ measurements in a **charge detector** (SCD) at the top of the instrument

Example of a typical space-borne CR experiment with a generic charge detector (silicon pixels, scintillator paddles/tiles, etc.)

Backscattering (BS) from the calorimeter generates fake hits in the charge detectors and in the tracker.

The tracker back estrapolates to the SCD with an impact point IP residual ~ $150 - 200 \mu m$

BS increases with energy and deteriorates the charge ID of individual CR elements.

ADA-5D concept: reject BS with a high resolution ToF measurement



Arrival time (ns) of BS from calorimeter on SCD: a GEANT4 simulation



- filled-green: back-scattered photons (interact in SCD \rightarrow ionizing secondaries \rightarrow fake hits;
- filled-blue: back-scattered neutrons;
- filled-orange: back-scattered electrons (depositing energy in the charge detector);
- filled-red: incident protons on the charge detector (generated at t=0);
- unfilled histogram: inclusive of all above.

Nota "storica" Matrix-CSN5-2005-7

All'epoca (~15 anni fa !) con rivelatori SILICON PAD (next slide), abbiamo misurato risoluzioni in carica fra 0.2 e 0.3 dal Boro (Z=5) fino al Fe (Z=26) al **GSI** con un fascio primario di ⁶⁴Ni (1.0–1.3 GeV/amu) su fragmentation target di Be. La risoluzione in carica per protoni (Z=1) era ~0.1



Nota "storica" Matrix-CSN5-2005-7

Silicon Pad Array

- Pixel area: 1.125 × 1.125 cm²
- Thickness: 500 µm
- Matrix: 8 × 8 pixels
- Active area: 9.07 × 9.07 cm²
- TILE Full area: 9.47 × 9.47 cm²
 - Full depletion voltage: < 30V
 - Breakdown voltage: > 200V
 - Dark current per pixel: < ~ 1nA
 - Junction capacitance per pixel : ~ 25pF







Charge Identification with CHD and IMC



An example: CALET on the ISS



CHD – Charge Detector

- 2 layers x 14 plastic scintillating paddles
- single element charge ID from p to Fe and above (Z = 40)
- charge resolution ~0.1-0.3 e

IMC – Imaging Calorimeter

- Scifi + Tungsten absorbers: **3** X₀ at normal incidence
- 8 x 2 x 448 plastic scintillating fibers (1mm) readout individually
- Tracking (~0.1° angular resolution) + Shower imaging

TASC – Total Absorption Calorimeter 27 $X_{0,}$ 1.2 λ_{I}

- 6 x 2 x 16 lead tungstate (PbWO₄) logs
- Energy resolution: ~2 % (>10GeV) for e , γ ~30-35% for p, nuclei e/p separation: ~10^-5

Deviation from Z² response is corrected both in CHD and IMC using a core + halo ionization model (Voltz)

CALET is taking data aboard the ISS since 2015

Spectra of cosmic-ray nuclei from C to Fe



37th ICRC 2021 - CALET - HIGHLIGHT TALK

Pier Simone Marrocchesi

An example: direct measurements of Fe and Ni fluxes with CALET on the ISS



CALET Nickel paper: Physical Review Letters 128, 131103 (2022)

CALET Iron paper: Physical Review Letters **126**, 241101 (2021)



ADA_5D Charge & Timing 5D detector: x,y,z, time, charge

VERY stringent requirements for a space experiment:

Charge measurement:

- very large dynamic range > 1000 MIP (for trans-iron elements DR ~ 1600 MIP)
- charge resolution for proton < 0.1 => 200-300 um sensors for primary ionization

Timing measurement:

- sub-ns resolution (e.g., for 10 - 20 cm flight path \rightarrow needs 100 ps resolution)

Space resolution and granularity:

- modest granularity (3mm x 3mm pixels) to cover large O(m²) sensitive area)
- an independent TRACKER is in charge of the fine spatial resolution

Power budget:

- VERY challenging < 150 W/m^2

Radiation hardness:

- modest problem for space experiments < 10¹¹ 1 MeV neq (TID ~100 krad)

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Proposed development of LGADs for ADA-5D at FBK

- large pixels (e.g.: 3mm x 3mm)
- sensor thickness 200-300 um





mini-TILE (2.4cm x 2.4 cm): 16 FE = 8 x 8 LGADs



TILE (9.6 cm x 9.6 cm): 16 mini-tiles = 256 FE = 16 x 8 x 8 = 1024 LGADs





Each FE chip, connected to 4 LGADS, implements:

- double gain linear range to cover > 1000 m.i.p.
- internal ADC
- internal TAC + ADC conversion
- Track & Hold



Example of a portion of 2 staggered layers:

- no detector material above 1st layer
- estimate of 1st layer material budget:
 - G10-FR4 (3mm) : 16.88 cm RL => $X_0(\%)$ = 0.03/16.88 = 0.178 ○ LGAD (300µm) Si: 9.47 cm RL => $X_0(\%)$ = 0.03/9.47 = 0.317 Worst case: LGAD+G10+FE chip ~ 0.178 x 2 + 0.317 = **0.67% RL**
- Assuming a thin window (protection of first layer LGADs) + structural stiffners => requirement: < 1% RL

ADA-5D Development plan (2023)

4 parallel developments:

- $300\mu m$ thick LGAD sensor (FBK, TIFPA)
- FE chip (Pavia)
- digital readout (Pisa, Padova)
- system level: DAQ and beam tracker (Siena)
- 1st LGAD run @FBK

After LGAD production:

- $\circ~$ lab characterization of single LGAD sensors
- mechanical assembly and micro-bonding of 1 FE pixel (2x2 LGADs)
- 1st submission of r/o chip

After 1st r/o chip production:

- o lab characterization of FE chip
- 1st prototype of 1 PIXEL (2x2) LGADs
- $\circ~$ characterization and beam test (with ions) of PIXEL
- development of MINI-TILE prototype (16 pixels)
- characterization and beam test (with ions) of MINI-TILE

ADA_5D timeline over 3 years (Gantt chart)

ID	Task Name	Year	1						N	/ear 2	2	`						_	Year	3								Yea	ar 4
		JF	MA	M	JJ	A S	s o	NC	5	JF	M	A I	M J	J	A	sc	N	D	JI	FM	A	M	JJ	A	S	0 1	D	J	F
1	WP1 - Phase I							-																					
2	LGAD Simulation and design (FBK)																												
3	LGAD 1st batch production @FBK																												
4	1st batch characterization & delivery						ú																						
5	WP1 - Phase II								١	-							•												
6	(mini-)tile design (FBK)										1	1																	
7	(mini-)tile production @FBK											1																	
8	2nd batch characterization and delivery															min	"]												
9	WP2 - Phase I								-																				
10	FE chip design		1 1													Ì													
11	FE chip 1st version - production			Ě			-																						
12	1st FE chip - characterization																												
13	FE integration with LGAD test structures							ú																					
14	MS-1: fist LGAD array test structure								•	12/2	1																		
15	WP2 - Phase II								١											-									
16	design of 2nd version of FE chip											בי																	
17	production of 2nd version of FE chip											-	1	1 1	1	1													
18	integration & test with LGAD array																1			-									
19	WP3 - Phase I								•																				
20	design & simulation of 1st digital board	1																											
21	production + electrical tests of 1st board				Ľ	1			3																				
22	WP3 - Phase II								1															7					
23	digital r/o integration LGAD test structure															-		1											
24	design of 2nd version of digital board										1		1]															
25	production & test of 2nd digital board													Č			-	-											
26	integration & test with LGAD arrays																			1	1			•]					
27	MS-2: LGAD array prototype																	٠	12/1	9									
28	WP4 - Phase I																-												
29	integration of TIMEPIX3 in beam tracker																												
30	CR muon tests with tbeam tracker in lab															1	-												
31	WP4 - Phase II										-							-											
32	source tests with ADA-5D test structures														_		-												
33	1st beam test with ADA-5D test structures																												
34	WP4 - Phase III																		-		-				+			•	
35	source tests with prototype																								-	l			
36	2nd beam test with final prototype																												
37	data analysis																						mm				inn	3	
38	MS-3: final prototype																										٠	12/2	20

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	ADA-5D 2023 - FTE	PI/SI	PV	TIFPA	PD
Pier Simone Marrocchesi	PO Univ. di Siena + INFN Gruppo Collegato	0.7			
Paolo Maestro	PA Univ. di Siena + INFN Gruppo Collegato	0.4			
Gabriele Bigongiari	PA Univ. di Siena + INFN Gruppo Collegato	0.6			
Caterina Checchia	Assegno di ricerca - Univ. di Siena - Associaz. INFN Pis	0.6			
Mina Maghami Moghim	Dottoranda Univ. di Siena - Associaz. INFN Pisa	1.0			
Paolo Brogi	RTDA Univ. di Siena + INFN Gruppo Collegato	0.8			
Francesco Stolzi	RTDA Univ. di Siena + INFN Gruppo Collegato	0.6			
Alberto Messineo	PA Univ. di Pisa + INFN Pisa	0.1			
Lodovico Ratti	PO Univ. di Pavia		0.3		
Piero Malcovati	PO Univ. di Pavia		0.3		
Marco Grassi	RTDB Univ. di Pavia		0.5		
Joana Minga	Dottoranda (associata sez. Pavia)		1.0		
Simone Giroletti	Dottorando (associato sez. Pavia)		1.0		
Carla Vacchi	RC Univ. di Pavia		0.4		
Lucio Pancheri	PA Univ. di Trento			0.4	
GianFranco Dalla Betta	PO Univ. di Trento			0.1	
Thomas Corradino	Dottorando (associato TIFPA)			0.5	
Alberto Taffelli	Dottorando (associato TIFPA)			0.8	
Maurizio Boscardin	FBK Ricercatore Senior (associato TIFPA)			0.1	
Matteo Centis Vignali	FBK (associato TIFPA)			0.1	
Omar Hammad Ali	FBK (associato TIFPA)			0.2	
Gianmaria Collazuol	PA Univ. di Padova				0.2
Marco Mattiazzi	Dottoranda (associata sez. Padova)				0.7
Matteo Feltri	Post-doc (associato sez. Padova)				0.3
TOTALE FTE	11.7	4.8	3.5	2.2	1.2
F.Morsani	Tecnologo INFN Pisa	0.1			
Stiaccini Leonardo	Tecnico Università di Siena	0.5			

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	ADA_5D 2023 - PREVENTIVI	PI/SI	PV	TIFPA	PD	TOT
Missioni	missioni in Italia (no beam test nel 2023)	4.5	2	2	2	10.5
Consumo	elettronica	11.5	4	4	10	29.5
Costruzione Apparati	LGAD (FBK) + FE ASIC (PV)		24	27.5		51.5
Inventariabile						0
TOTALE richieste x 2023		16	30	33.5	12	91.5

•	ADA_5D 2023 - 2025	2023	2024	2025
Missioni	beam tests (sj)		15	15
	missioni in italia	10.5	6	6
Consumi	<u>componentistica elettronica</u> + <u>meccanica</u> + <u>schede</u>	26	25	28
~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~	tracker upgrade	3.5	6	
	runs di produzione del chip di front-end	24	42	
Apparati	runs di produzione di LGADs a FBK	27.5	26	
	TOTAL 260.5	91.5	120	49

#### ADA-5D: Richieste di servizi in sezione per il 2023

- Supporto gruppo alte-tecnologie (micro-bonding)
- Supporto progettazione elettronica (<u>2 mesi uomo</u>)
- Eventuale uso della stampante 3D (A. Basti)
- utilizzo del laboratorio di HERD/ASAP (ASAP in chiusura nel 2022)